

S/N TBD
Docket: CS01-150
Group art unit : ___ TBD

Date July 18, 2003

To: Commissioner of Patents and Trademarks
P.O. Box 1450 Alexandria, VA 22313-1450

Fr: William J. Stoffel Reg. No. 39,390 Cust No. 30402
PMB 455
1735 Market St - Suite A
Philadelphia, PA 19103

Subject:

Serial No. TDB
Docket CS1-150
File Date: with application
Inventor: Sheldon C. P. Lim

Title: A Method for Detecting and Monitoring Defects
Group art unit: TBD

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO A820 (also PTO-1449), Information Disclosure Citation and references.

CERTIFICATE OF MAILING OR EXPRESS MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail or express mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450, on July 18, 2003.

Signature/Date William J. Stoffel 7/18/03

William J. Stoffel Reg. No. 39,390
Customer number 30402

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The following Patents and/or Publication are submitted to comply with the duty to disclose under CFR 1.97-1.99 and 37 CFR 1.56. Copies of each document is included herewith.

US 6,403,389B1(Chang et al.) shows a method for measuring sheet resistance.

US 5,627,101(Lin et al.) shows a test method for a electro migration using a Metal and Poly test structure.

US 5,987,398(Halverson et al.) shows a method for SPC for a process having a non-constant mean of a response variable.

US 5,883,437(Maruyama et al.) discloses a method for applying a time varying voltage between the electrode and wiring pattern at different locations so as to detect a current flow and determine a defect by a variation in the detected current flow at the different locations and a portion of the defect.

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US 6,466,038 (Pekin, et al.) shows a method for non-isothermal electro migration testing of interconnects.

US 5,514,974 (Bouldin) shows a method for testing for metal failures by using 2 different test structures.

US 6,087,189 (Huang) shows test structure to monitor silicide.

US 5,552,718 (Bruce et al.) shows a test structure for space and line measurement.

Plusquellec et al., "Identification of defective CMOS devices using Correlation and Regression Analysis of Frequency Domain Transient Signal data", retrieved from website <http://www.csee.umbc.edu/~plusquel/pubs/itc97.pdf> on about May 20, 2003. No publication date listed.

Sincerely,



William J. Stoffel

Reg. No. 39,390

Customer number 30,402

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Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1of 2***Complete if Known***

Application Number	tbd
Filing Date	
First Named Inventor	Lim
Art Unit	
Examiner Name	

Attorney Docket Number CS01-150**U. S. PATENT DOCUMENTS**

Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
		US- 6,403,389B1 ✓	06/11/2002	Chang et al	
		US- 5,627,101 ✓	5/6/1997	Lin et al.	
		US- 5,987,398 ✓	11/16/1999	Halverson et al.	
		US- 5,883,437 ✓	3/16/1999	Maruyama et al.	
		US- 6,466,038 ✓	10/15/2002	Pekin	
		US- 5,514,974 ✓	5/7/1996	Bouldin	
		US- 6,087,189 ✓	7/11/2000	Huang	
		US- 5,552,718 ✓	9/3/1996	Bruce	
US-					

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ⁶
		Country Code ³ Number ⁴ Kind Code ⁵ (if known)				

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This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>				Complete if Known	
				Application Number	TBD
				Filing Date	
				First Named Inventor	Lim
				Art Unit	
				Examiner Name	
Sheet	2	of	2	Attorney Docket Number	cs01-50

NON-PATENT LITERATURE DOCUMENTS

Examiner Signature		Date Considered	
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